IEEE HOME ! SEARCH IEEE ! SHOP ! WEB ACCOUNT ! CONTACT IEEE **�IEEE** Publications/Services Standards Conferences Welcome **United States Patent and Trademark Office RELEASE 1.5** Search Results FAQ Terms TEEE Quick Uniks Welcome to IEEE Xplore Your search matched 5 of 987057 documents. O- Home - What Can A maximum of 5 results are displayed, 25 to a page, sorted by Relevance in descending | Access? O- Log-out You may refine your search by editing the current search expression or entering a new one **Tables of Contents** the text box. Then click Search Again. O- Journals & Magazines ((nor) <sentence> (flash) <sentence> (eeprom)) and state O- Conference **Proceedings** Search Again O- Standards Results: Search Journal or Magazine = JNL Conference = CNF Standard = STD O- By Author O- Basic 1 A self-convergence erase for NOR flash EEPROM using O- Advanced avalanche hot carrier injection Member Services Yamada, S.; Yamane, T.; Amemiya, K.; Naruke, K.; O- Join IEEE Electron Devices, IEEE Transactions on , Volume: 43 Issue: 11 , Nov. O- Establish IEEE 1996 Web Account Page(s): 1937 -1941 O- Access the **IEEE Member Digital Library** Print Format [Abstract] [PDF Full-Text (472 KB)] IEEE JNL

2 Mobile ion-induced data retention failure in NOR flash memory cell

Lee, W.H.; Dong-Kyu Lee; Keon-Soo Kim; Kun-Ok Ahn; Kang-Deog

Device and Materials Reliability, IEEE Transactions on . Volume: 1

Issue: 2 , June 2001

Page(s): 128 -132

[Abstract] [PDF Full-Text (152 KB)] IEEE JNL

3 A channel-erasing 1.8 V-only 32 Mb NOR flash EEPROM with a bit-line direct-sensing scheme

Atsumi, S.; Umezawa, A.; Tanzawa, T.; Taura, T.; Shiga, H.; Takano, Y.; Miyaba, T.; Matsui, M.; Watanabe, H.; Isobe, K.; Kitamura, S.; Yamada, S.; Saito, M.; Mòri, S.; Watanabe, T.; Solid-State Circuits Conference, 2000. Digest of Technical Papers. ISSCC. 2000 IEEE International, 7-9 Feb. 2000 Page(s): 276 -277, 464-5

[Abstract] [PDF Full-Text (325 KB)] IEEE CNF

4 A flash IC card with programmable security code

Liu Kai; Pan li-yang; Zhu jun;

ASIC, 2001. Proceedings. 4th International Conference on , 23-25

Oct. 2001

Page(s): 584 -587

[Abstract] [PDF Full-Text (314 KB)] IEEE CNF

5 A channel-erasing 1.8-V-only 32-Mb NOR flash EEPROM with a bitline direct sensing scheme

Atsumi, S.; Umezawa, A.; Tanzawa, T.; Taura, T.; Shiga, H.; Takano, Y.; Miyaba, T.; Matsui, M.; Watanabe, H.; Isobe, K.; Kitamura, S.; Yamada, S.; Saito, M.; Mori, S.; Watanabe, T.;

Solid-State Circuits, IEEE Journal of , Volume: 35 Issue: 11 , Nov.

2000

Page(s): 1648 -1654

[Abstract] [PDF Full-Text (152 KB)] IEEE JNL

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ | Terms | Back to Top

Copyright © 2003 IEEE - All rights reserved